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ICS 31.080.01
CCS L 40

NATIONAL STANDARD OF THE PEOPLE'S REPUBLIC OF CHINA

GB/T 20521.4-2025

Semiconductor devices - Part 14-4: Semiconductor sensors - Semiconductor accelerometers

半导体器件 第14-4部分：半导体传感器 半导体加速度计

(English Translation)

Issued on: December 31, 2025 **Implemented on: July 1, 2026**

Issued by: State Administration for Market Regulation, Standardization Administration of China

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1 Foreword

GB/T 20521.4-2025 was issued by State Administration for Market Regulation, Standardization Administration of China on 31 December 2025 and has been in force since 1 July 2026.

It is one of 6 parts of the GB/T 20521 series.

The GB/T prefix marks a recommended standard. It is not law in itself: it becomes binding when a contract names it, when a regulation or a mandatory standard refers to it, or when a producer declares conformity with it.

2 Scope Preview

GB/T 20521.4-2025 falls under ICS 31.080.01, in the field of electronics.

This catalogue holds 1,274 other GB/T standards in that field.

In this catalogue, GB/T standards carry edition years from 1963 to 2026.

3 About this standard

Issued by: State Administration for Market Regulation, Standardization Administration of China

English translation: about 52 pages

Chinese original: about 78,772 characters

4 Related standards

Other parts of this standard:

GB/T 20521-2006 - Semiconductor devices - Part 14-1: Semiconductor sensors - Generic

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specification for sensors

GB/T 20521.1-2026 - Semiconductor devices - Part 14-1: Semiconductor sensors - Generic specification for sensors

GB/T 20521.2-2025 - Semiconductor devices - Part 14-2: Semiconductor sensors - Hall elements

GB/T 20521.5-2025 - Semiconductor devices - Part 14-5: Semiconductor sensors - PN-junction semiconductor temperature sensor

GB/T 20521.12-2026 - Semiconductor devices - Part 14-12: Semiconductor sensors - Performance test methods for CMOS imager-based gas sensors

5 Classification and status

International classification (ICS): 31.080.01

Chinese Standard Classification (CCS): L 40

Prefix GB/T: recommended standard.

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